

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|---------|--|---|------------------|---------|------------------|
| L2 | 55 | ((CHUNG-SAM) near2 (JUN)).INV. | US-PGPUB; USPAT; USOCR | OR | ON | 2007/02/16 13:14 |
| L3 | 59 | ((SANG-MUN) near2 (CHON)).INV. | US-PGPUB; USPAT; USOCR | OR | ON | 2007/02/16 13:19 |
| L4 | 24 | ((SUN-YONG) near2 (CHOI)).INV. | US-PGPUB; USPAT; USOCR | OR | ON | 2007/02/16 13:21 |
| L5 | 35 | ((DONG-JIN) near2 (PARK)).INV. | US-PGPUB; USPAT; USOCR | OR | ON | 2007/02/16 13:22 |
| L6 | 8 | ((JEONG-HYUN) near2 (CHOI)). INV. | US-PGPUB; USPAT; USOCR | OR | ON | 2007/02/16 13:24 |
| S1 | 37073 | fft or fast adj fourier adj transform | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | AND | ON | 2007/02/15 12:57 |
| S2 | 37073 | fft or (fast adj fourier adj transform) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | AND | ON | 2007/02/15 12:57 |
| S3 | 69458 | (scanning adj electron adj microscope) or (electron adj microscope) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | AND | ON | 2007/02/15 12:58 |
| S4 | 332 | S2 and S3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | AND | ON | 2007/02/15 12:58 |
| S5 | 3245791 | (sample) or (wafer) or (IC) or (integrated adj circuit) or (IC adj chip) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | AND | ON | 2007/02/15 13:00 |

EAST Search History

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|-----|-------|---|---|-----|----|------------------|
| S6 | 303 | S4 and S5 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | AND | ON | 2007/02/15 13:00 |
| S7 | 69630 | (inspect\$3 or analyzing or determining or finding) same (defects or abnormalities) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | AND | ON | 2007/02/15 13:01 |
| S8 | 74077 | (inspect\$3 or analyzing or determining or finding or discrimi\$5) same (defects or abnormalities) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | AND | ON | 2007/02/15 13:02 |
| S9 | 69 | S6 and S8 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | AND | ON | 2007/02/15 13:02 |
| S10 | 63 | etching same trace same (line adj width) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | AND | ON | 2007/02/15 13:04 |
| S12 | 7 | ("4242635" "4466746" "4668916" "4682857" "6121059" "6559670" "6657447").PN. OR ("6842021"). URPN. | US-PGPUB; USPAT; USOCR | OR | ON | 2007/02/15 13:19 |